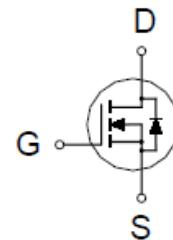
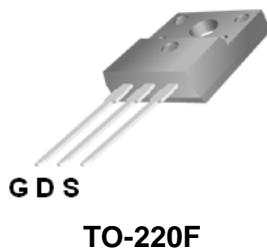


P2610ATFG

N-Channel Enhancement Mode MOSFET

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
100V	26mΩ @ $V_{GS} = 10V$	31A



100% UIS tested

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		V_{DS}	100	V
Gate-Source Voltage		V_{GS}	± 20	
Continuous Drain Current	$T_C = 25^\circ C$	I_D	31	A
	$T_C = 100^\circ C$		19	
Pulsed Drain Current ¹		I_{DM}	130	
Avalanche Current		I_{AS}	77	
Avalanche Energy	$L = 0.3mH$	E_{AS}	900	mJ
Power Dissipation	$T_C = 25^\circ C$	P_D	50	W
	$T_C = 100^\circ C$		20	
Operating Junction & Storage Temperature Range		T_J, T_{STG}	-55 to 150	°C
Lead Temperature ($1/16"$ from case for 10 sec.)		T_L	275	

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$	2.5	2.5	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	
Case-to-Heatsink	$R_{\theta CS}$		0.5	

¹Pulse width limited by maximum junction temperature.

P2610ATFG

N-Channel Enhancement Mode MOSFET

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	100			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	1.5	2.3	4.0	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 20\text{V}$			± 250	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 80\text{V}, V_{\text{GS}} = 0\text{V}$			1	μA
		$V_{\text{DS}} = 80\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$			10	
On-State Drain Current ¹	$I_{\text{D}(\text{ON})}$	$V_{\text{DS}} = 10\text{V}, V_{\text{GS}} = 10\text{V}$	31			A
Drain-Source On-State	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 10\text{V}, I_D = 25\text{A}$		21	26	$\text{m}\Omega$
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = 40\text{V}, I_D = 25\text{A}$		38		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 25\text{V}, f = 1\text{MHz}$		4900		pF
Output Capacitance	C_{oss}			887		
Reverse Transfer Capacitance	C_{rss}			186		
Total Gate Charge ²	Q_g	$V_{\text{DS}} = 80\text{V}, V_{\text{GS}} = 10\text{V}, I_D = 50\text{A}$		79		nC
Gate-Source Charge ²	Q_{gs}			31		
Gate-Drain Charge ²	Q_{gd}			30		
Turn-On Delay Time ²	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = 50\text{V}, I_D \geq 30\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GS}} = 25\Omega$		25		nS
Rise Time ²	t_r			250		
Turn-Off Delay Time ²	$t_{\text{d}(\text{off})}$			110		
Fall Time ²	t_f			140		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ\text{C}$)						
Continuous Current	I_S				31	A
Forward Voltage ¹	V_{SD}	$I_F = I_S, V_{\text{GS}} = 0\text{V}$			1.5	V
Reverse Recovery Time	t_{rr}			100		nS
Reverse Recovery Charge	Q_{rr}			380		nC

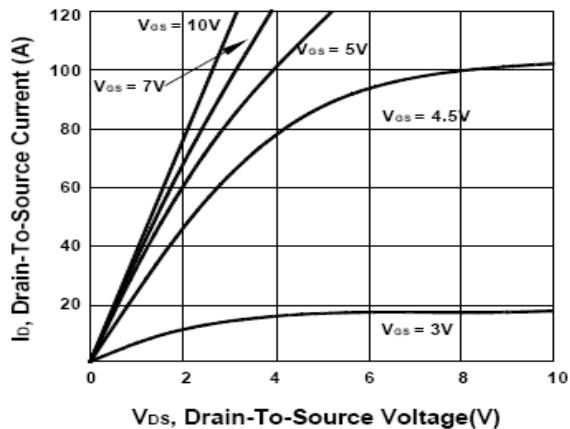
¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

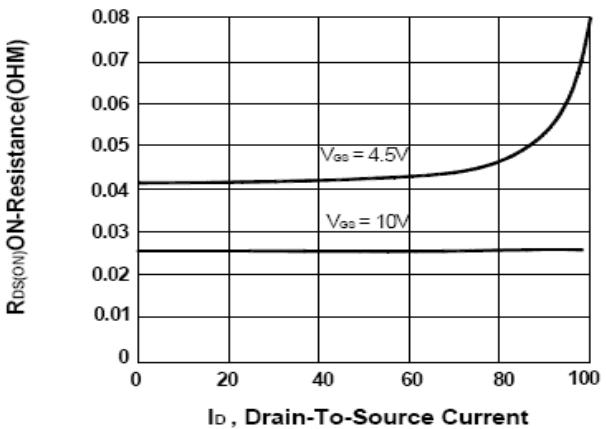
P2610ATFG

N-Channel Enhancement Mode MOSFET

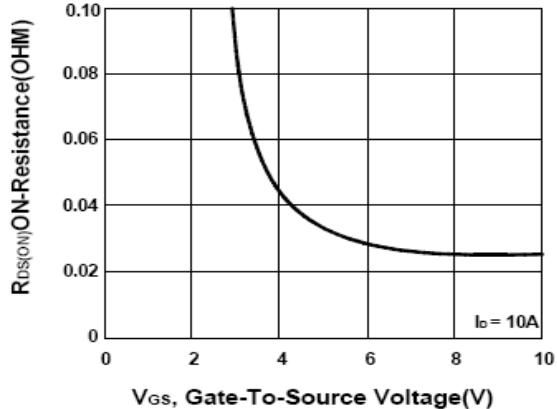
Output Characteristics



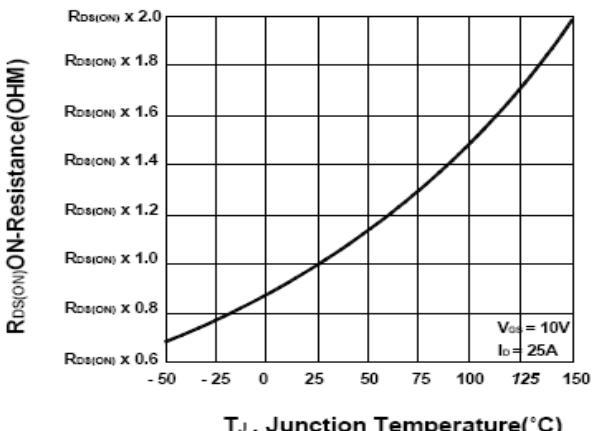
On-Resistance VS Drain Current



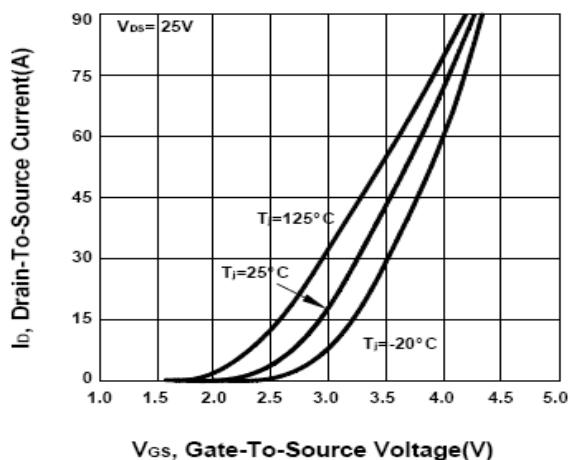
On-Resistance VS Gate-To-Source



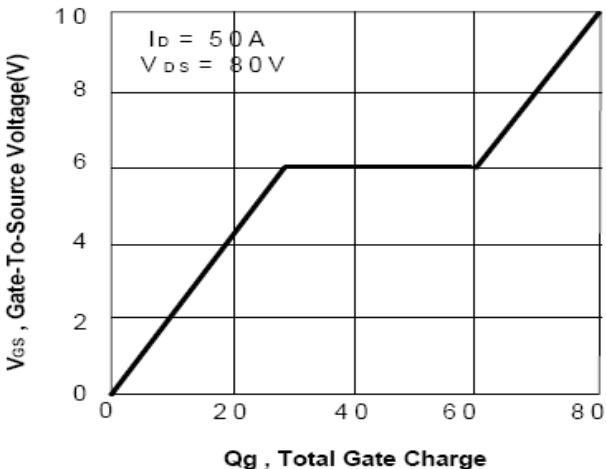
On-Resistance VS Temperature



Transfer Characteristics

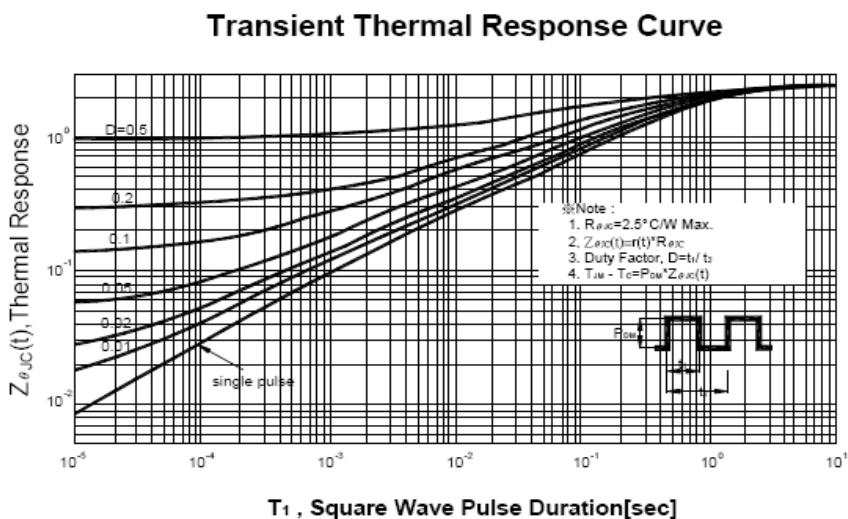
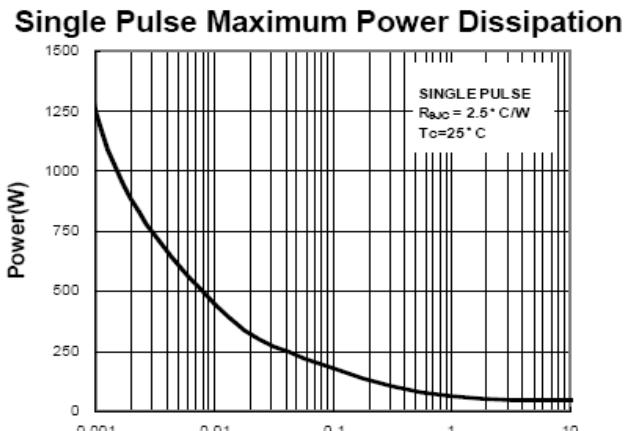
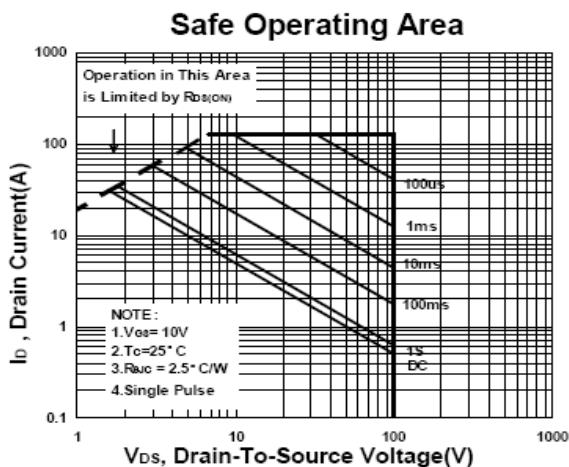
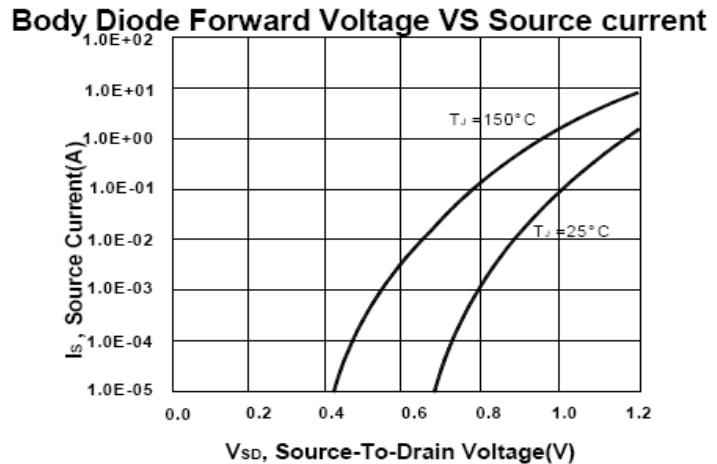
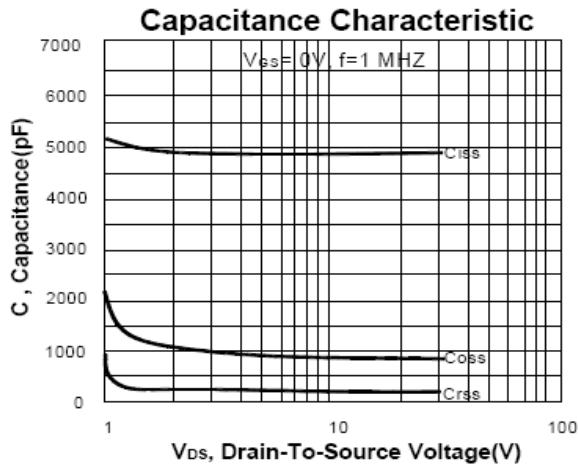


Gate charge Characteristics



P2610ATFG

N-Channel Enhancement Mode MOSFET



P2610ATFG

N-Channel Enhancement Mode MOSFET

Package Dimension

TO-220F (3-Lead) MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	4.2		4.93	e	2.05	2.55	3.05
A1	2.34		3.1	F	27.45		30.6
B	17.77		20.3	G	7.72		9.3
b	0.6		1.05	H	6.1		7.1
b1	0.9	1.23	1.62	L	12.5		14.5
b2	0.6		1.9	L1	1.97		3.8
c	0.4		1.0	P	2.98		3.4
D	14.7		16.4	Q	2.1		2.96
D1	6.4		7.5	q	3.0		3.8
E	9.7		10.4				

